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Fast analysis for RoHS & WEEE

EDX3000D





ALL-NEW UNIQUE VIDEO POSITIONING SYSTEM!

Energy Dispersive X-Ray Fluorescence Spectrometer

EDX 3000D



More accurate testing results are always the persistent pursuit of Skyray people and we still keep in mind that we provide better services for our customers.

Newly developed EDX 3000D inherits this idea. It not only inherits the five characteristics of accuracy, rapidness, non destructive, direct viewing and environmental protection of Skyray EDX series spectrometers, but also adopts patented product SNE of Skyray to increase the accuracy of testing results.

Sample chamber with newly added automatic switch makes operation more convenient, and automatic sample platform newly designed assures accurate testing.

Technical specifications

Model: EDX 3000D

Analytical range of elements: From sulfur (S) to uranium (U)

Analysis range: 1ppm-99.99%

Detection limit: The detection limit can reach 1ppm for hazardous substances

(Cd/Pb/Cr/Hg/Br) restricted in RoHS directive

Measurement time: 60~200s

Revolution: Energy revolution is 155±5eV

High voltage: 5~50kV Tube current: 50~1000 µ A

Ambient temperature range: 15~30°C

Power supply: AC 220 ±5V (AC purified stabilized voltage power supply is suggested)

3-D super-large sample chamber and the size is \$\Phi 450x90mm\$

24 elements can be analyzed simultaneously

Weight: 110kg

Configurations

Movable sample platform

Enhanced metal element sensitivity analyzer

Amplifier circuit

Signal-to-Noise Enhancer (SNE)

PC and ink-jet printer

Performance

Automatic filters switching system

Automatic collimators switching system

Triple safety protection mode

Independent matrix effect correction models

Multi-variable non-linear regression procedure

Sample chamber can be opened and closed automatically

Software positions sample platform and minimum displacement is 0.01mm

EDX 3000D

EDX 600

EDX 660

EDX 2800

EDX 3000

EDX 3000B

EDX 3000C

EDX 3000D

EDX 3600

EDX 3600B

EDX 6000

EDX 8000

EDX Pockket-I





Open and close sample chamber automatically





Automatic collimator and filter switch, for samples of different sizes

Used for RoHS substances, plating coating and full element analysis, one machine for multiple purposes

Electro-refrigeration Si PIN semiconductor detector, with no liquid nitrogen refrigeration

Specially developed measurement software, with user friendly operation interface

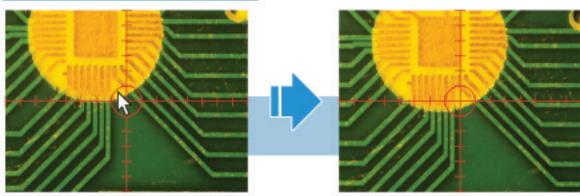
Inbuilt high resolution camera, convenient for users to analyze samples at any moment

An attractive and fashionable design

Precise automatic movable platform, can adjust the position of sample more accurately and conveniently

Unique light path enhancement system, convenient for users to observe samples more accurately

Sample positioning system newly developed with automatic movable platform, starts measurement with one mouse click



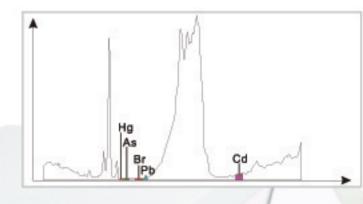
Click the part to be tested in the sample view, EDX 3000D will move the sample to specified location and test it

Examples

Plastic



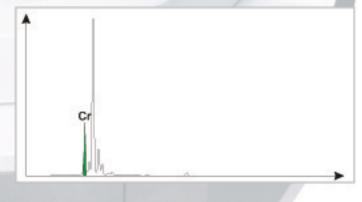
Spectrum



Stainless steel



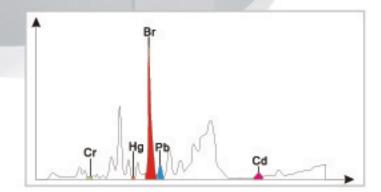
Spectrum



PCB



Spectrum





Plastics

SKYRAYINSTRUMENT

What is RoHS and WEEE Directive?

On 13 Feb, 2003, European Union issued Directive 2002/95/EC on RoHS and Directive 2002/95/EC on WEEE. The EU directives RoHS and WEEE have been implemented. New electrical and electronic equipment put on the market from 1 July 2006 shall not contain lead(Pb), mercury(Hg), cadmium(Cd), hexavalent chromium(Cra+), polybrominated biphenyls(PBBs) or polybrominated diphenyl ethers(PBDEs).

Testing standards for substances restricted by RoHS Directive

Hazardous substances	Standards (mg/kg)
Cd	100
Pb	1000
Hg	1000
Br(PBBs & PBDEs)	1000
Cr**	1000

Restricted substances and their typical uses

Pb		
Solders		
Paints	Pigments and driers	
Glass materials	Pb is allowed in fluorescent lamp	
Ceramic materials	Pb is allowed in certain electronic ceramic materials	
Iron, aluminum and copper materials		A certain amount of Pb is allowed
Plastic	PVC stabilizer and pigments	
Batteries	Pb is allowed in acidic batteries for vehicles	

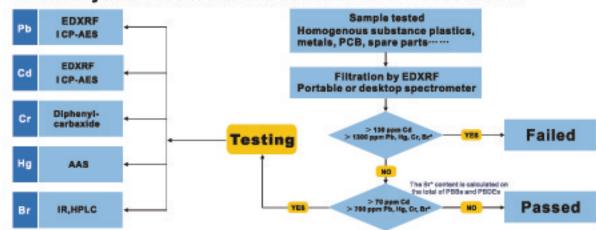
Cd		
Plastics	Stabilizer and pigments	
Solders	Seldom used	
Ceramic materials	Seldom used	
Connectors	Relays and switches	
Batteries	Cd is allowed in Ni-Cd batteries	
Semiconductors	Optical sensors and solar cell panels	

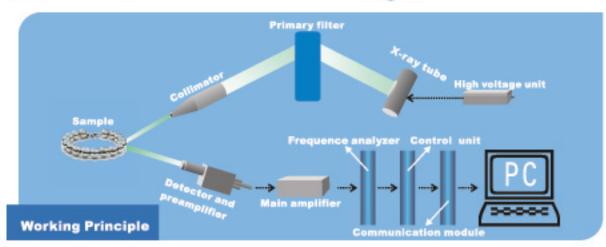
Hg		
Batteries	Prohibited (see battery directive)	
Connectors	Relays and sensitive switches	
Fluorescent lamps	A certain amount of Hg is allowed	

Passivation layers	Commonly used for naked metal surfaces to enhance adhesion of plating layers
Anti-corrosive plating layers	Painting and plating layers
Chrome plating layers	Plating layer of chromium metal is not under control
Plasticizer	Commonly used to plastics plating process but not final products

Brominated flame retardants

The analytical method of filtration for RoHS substances





Characteristic X-rays of elements

Each element will emit X-ray with its own energy when it is excited, this characteristic X-ray is called X-ray fluorescence. That is the basis for analysis.

Scatting

It is the background of the spectrum.

Photoelectron

It is what the detector analyzes.

The X-ray fluorescence intensities of interested elements in the sample are I1, I2, I3, I4, I3 etc. And the element content is a function of X-ray fluorescence intensity I of the element. The general formula is as follows:

C=f(I1, I2, I3, I4, I5.....)

The function is too complicated to calculate, and the empirical formula is as follows:

C=Kılı+Kılı+Kılı+Kılı+Kılı+Kılı

C means

The content of element in the sample.

X-ray fluorescence intensities of elements in the sample respectively.

K1, K2, K3....mean

Coefficients to be calculated.

The coefficients K1, K2, K3.....can be determined with the samples of known contents though the establishment of scale merit.